


Search Notes 	Application/Control No. 10574286	Applicant(s)/Patent Under Reexamination OIKAWA ET AL.
	Examiner CEDRIC CHAN	Art Unit 1797

SEARCHED			
Class	Subclass	Date	Examiner
422	50,68,1,82,05,99,104	2/13/2010	CC
436	73	2/13/2010	CC

SEARCH NOTES		
Search Notes	Date	Examiner
inventor name search (PALM)	2/5/2010	CC
inventor name search (EAST)	2/13/2010	CC
searched US/Foreign databases – EAST/USPat,OCR,PGPub,EPO,JPO,Derwent	2/13/2010	CC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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